



MISSISSIPPI STATE
UNIVERSITY™

INVITATION FOR BIDS

OFFICE OF PROCUREMENT & CONTRACTS

1. INSTRUCTIONS FOR BIDDERS

- a. Sealed bids will be received in the Office of Procurement & Contracts, Mississippi State University, for the purchase of the items listed herein.
- b. All bids must be received in the Office of Procurement & Contracts on or before the bid opening time and date listed herein.
- c. Delivery of bids must be during normal working hours, 8:00 a.m. to 5:00 p.m. CST, except on weekends and holidays when no delivery is possible.
- d. Bidders shall submit their bids either electronically or in a sealed envelope.
 - i. Sealed bids should include the bid number on the face of the envelope as well as the bidders' name and address.
 - ii. For electronic submission, the bidder shall go to:
https://www.ms.gov/dfa/contract_bid_search
- e. All questions regarding this bid should be directed to the Office of Procurement & Contracts at 662-325-2550.
- f. The following address should be used for submitting your bid:
 - i. 245 Barr Avenue, 610 McArthur Hall, Mississippi State MS, 39762

2. TERMS AND CONDITIONS

- a. All bids should be bid "FOB Destination"
- b. Bidders must comply with all rules, regulations, and statutes relating to purchasing in the State of Mississippi, in addition to the requirements on this form.
- c. General Bid Terms and Conditions can be found here:
https://www.procurement.msstate.edu/procurement/bids/Bid_General_Terms_May_2019_V2.pdf

Bid Number: 19-48, RFX#3160002962

Opening Date: July 2, 2019

Description: X-Ray Diffraction Benchtop System

Vendor Name: _____

Vendor Address: _____

Telephone Number: _____

Days the Offer is Firm: _____

Authorized Signature: _____

Name: _____

Title: _____

Item	Quantity	Description	Unit Price	Total Price
1	1	X-Ray Diffraction Benchtop System – as per attached specifications		

System required:

Benchtop X-ray Diffraction System employing X-ray powder diffraction for qualitative and quantitative analysis.

Benchtop X-ray Diffractometer Requirements

- 0D/1D High Speed detector 12.8mm-20mm active area, 100 μ m pixels x 128 channels, 10⁶ cps/pixel count rate, Programmable energy resolution modes
- Variable Knife edge (VKE)
- 600W X-ray generator, High frequency, 0.60 kW, Power requirement 115V. 60Hz single phase, Interlocked radiation enclosure with X-ray light on, 1.3 kW Air-cooled Ultra Quiet heat exchanger
- Reliable Goniometer range -3° – 145° 2 θ /min, speed 0.01°- 100° 2 θ /min
- Slit assembly (scattering 8mm, soller 5° incident and receiving, and receiving 0.3 mm)
- X-ray tube 2.0 kW, Cu, Normal focus
- Accessories: Manual, NBS handbook, Ni k β filter for Cu radiation, Si reference specimen, Aluminum backfill sample holders, glass 0.2mm & 0.5mm depression, spring clips to mount slides, Direct beam Adsorber, Anti-scatter Protector
- Heating Stage with built in temperature control-ambient to 500°C for phase transitions/structural changes
- Air tight sample container for air sensitive materials

Computer Requirements

- PC Computer for Instrument control and data processing
- PC must include Intel Core i7 processor, 8.0 GB SDRAM, Internal audio speaker, 24" Flat screen monitor, Dual Monitor ability, 2x 500 GB Hard drive, RAID 1 mirror, 8x DVD+/- RW 9.5 optical Disk Drive, 4 USB ports, 6 USB3 Ports, keyboard, USB 2 button scroll mouse and pad, Microsoft Windows 10 PRO, 64 bit, MS office, Adobe Acrobat Standard DC, Color Printer with cable, 2 ethernet ports required and 3 year warranty

- Software: Measurement and Control Software, Data and Analysis software w/10 seat network license, Data manage plug-in, Powder Basic Analysis software, Powder Qualitative Search Analysis plug-in, Crystallography Open database with free download and renewals

Additional requirements

- Applications training (On-site or company provided)
- One year On-site repair, one year parts and labor with optional 2 years additional service
- 8-position sample changer/spinner (Include one Zero Background sample holder no indent)
- ICDD PDF-2 Database, FIZ/NIST Inorganic Crystal Structure database (ICSD) Academic